

18A 500V N-channel Enhancement Mode Power MOSFET

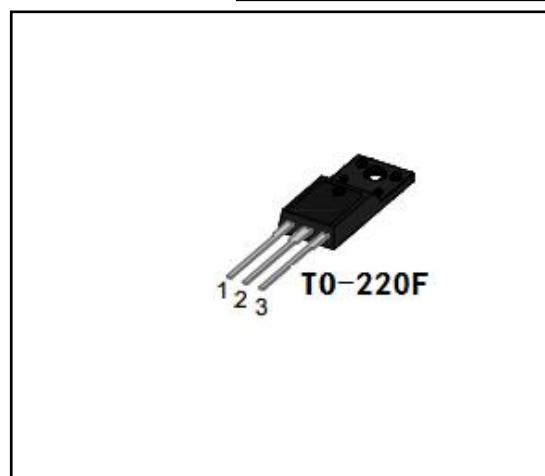
1 Description

These N-channel enhanced vdmosfets, is obtained by the self-aligned planar technology which reduce the conduction loss, improve switching performance and enhance the avalanche energy. Which accords with the RoHS standard. TO-220F provides insulation voltage rated at 2000V RMS from all three terminals to external heatsink. TO-220F series comply with UL standards (File ref:E252906).

	$V_{DSS} = 500V$ $I_D = 18.0A$ $R_{DS(on)} \text{ (TYP)} = 0.24\Omega$
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2 Features

- Fast switching
- ESD improved capability
- Low on resistance($R_{DS(on)} \leq 0.35\Omega$)
- Low gate charge(Typ: 52nC)
- Low reverse transfer capacitances(Typ: 16pF)
- 100% single pulse avalanche energy test
- 100% ΔV_{DS} test



3 Applications

- Used in various power switching circuit for system miniaturization and higher efficiency.
- Power switch circuit of electron ballast and adaptor.

4 Electrical Characteristics

4.1 Absolute Maximum Ratings ($T_c=25^\circ C$,unless otherwise noted)

PARAMETER		SYMBOL	VALUE	UNIT
Drian-Source Voltage		V_{DS}	500	V
Gate-Source Voltage		V_{GS}	± 30	V
Drain Current(continuous) ^(Note 3)		I_D	18	A
Drain Current(continuous)($T=100^\circ C$) ^(Note 3)		I_D	11	A
Drain Current(Pulsed)		I_{DM}	72	A
Single Pulse Avalanche Energy ^(Note 4)		E_{AS}	1050	mJ
Derating Factor above $T_a=25^\circ C$		P_D	0.34	W
Power Dissipation $T_c=25^\circ C$			43	W
Operating Junction Temperature Range		T_j	-55~150	°C
Storage Temperature Range		T_{stg}	-55~150	°C
High Temperature(tin solder)		T_L	300	°C

4.2 Thermal Characteristics

PARAMETER		SYMBOL	VALUE	UNIT
Thermal Resistance, Junction to Case-sink		R_{thJC}	2.98	°C/W
Thermal Resistance, Junction to Ambient		R_{thJA}	62.5	°C/W

4.3 Electrical Characteristics (T_c=25°C, unless otherwise noted)

PARAMETER	SYMBOL	Test Condition	VALUE			UNIT
			MIN	TYP	MAX	
Off Characteristics						
Drain-source Breakdown Voltage	BV _{DSS}	I _D =250μA,V _{GS} =0V	500	--	--	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =500V,V _{GS} =0V, T _c =25°C	--	--	1	μA
		V _{DS} =400V,V _{GS} =0V, T _c =125°C	--	--	100	μA
Gate-to-Body Leakage Current	I _{GSS}	V _{GS} =±30V,V _{DS} =0V	--	--	±100	nA
On Characteristics ^(Note 3)						
Gate threshold voltage	V _{GS(th)}	V _{DS} =V _{GS} ,I _D =250μA	2.0	--	4.0	V
Drain-source on Resistance	R _{DS(on)}	V _{GS} =10V,I _D =9A	--	0.24	0.35	Ω
Dynamic Characteristics						
Input Capacitance	C _{iss}	V _{GS} =0V,V _{DS} =25V, f=1.0MHz	--	2919	--	pF
Output Capacitance	C _{oss}		--	277	--	
Reverse Transfer Capacitance	C _{rss}		--	16	--	
Turn-on Delay Time	T _{d(on)}	ID=18A, VDD=250V, VGS=10V, RG=10Ω	--	34	--	ns
Turn-on Rise Time	t _r		--	65	--	
Turn-off Delay Time	T _{d(off)}		--	82	--	
Turn-off Fall	t _f		--	45	--	
Total Gate Charge	Q _g	ID=18A, VDD=400V, VGS=10V	--	52	--	nc
Gate-to-Source Charge	Q _{gs}		--	12.6	--	
Gate-to-Drain("Miller")C harge	Q _{gd}		--	18.6	--	
Drain-Source Diode Characteristics						
Diode Forward Voltage ^(Note 3)	V _{FSD}	V _{GS} =0V,I _s =18A	--	--	1.5	V
Continuous Source Current (BodyDiode) ^(Note 3)	I _s		--	--	18	A
Reverse Recovery Time	trr	T _J =25°C ,IF=18A, dI/dt=100A/μS,VGS=0V	--	535	--	ns
Reverse Recovery Charge	Qrr		--	5671	--	nc

Notes:

1: Repetitive rating, pulse width limited by maximum junction temperature.

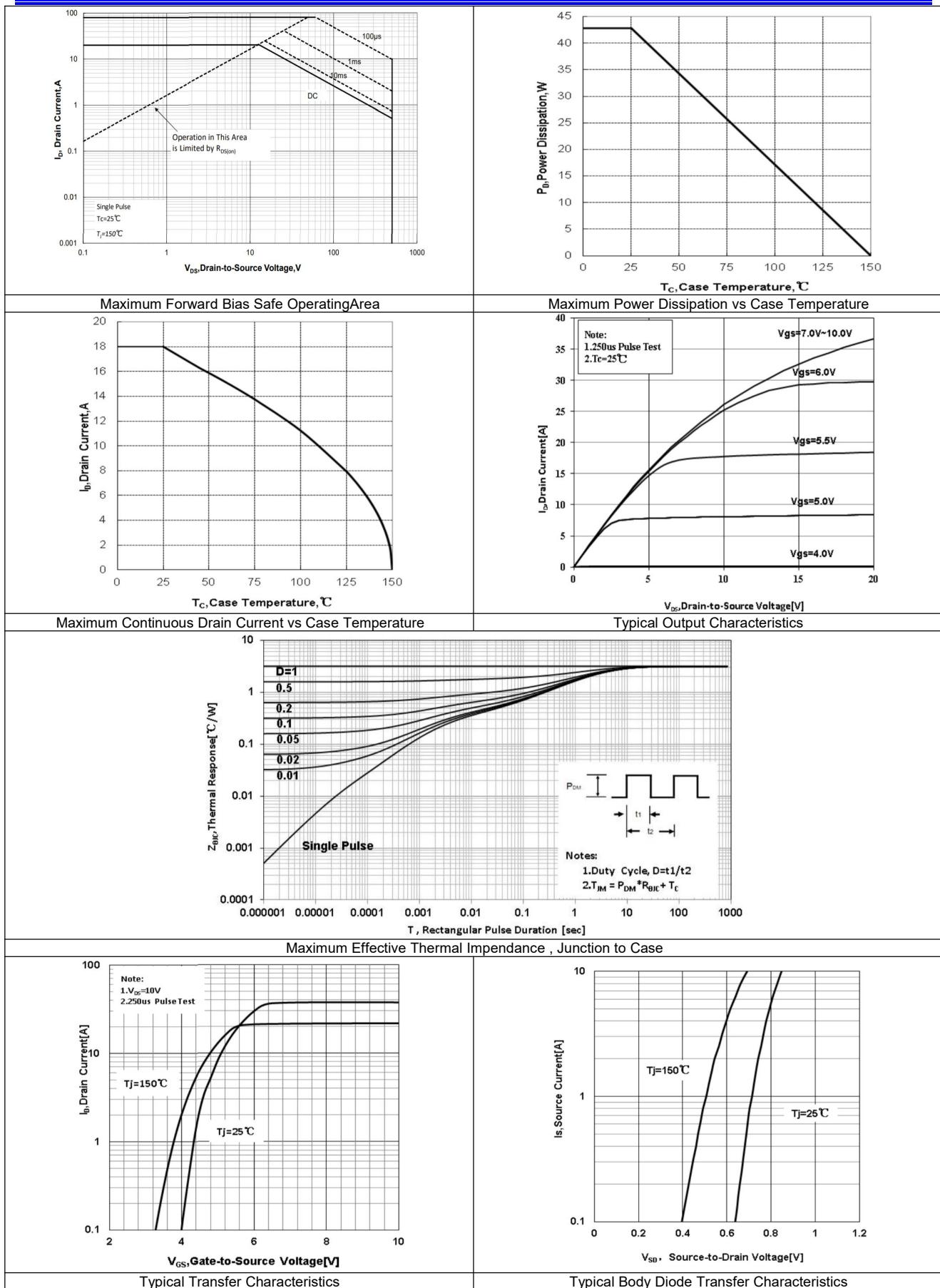
2: Surface mounted on FR4 Board, t≤10sec.

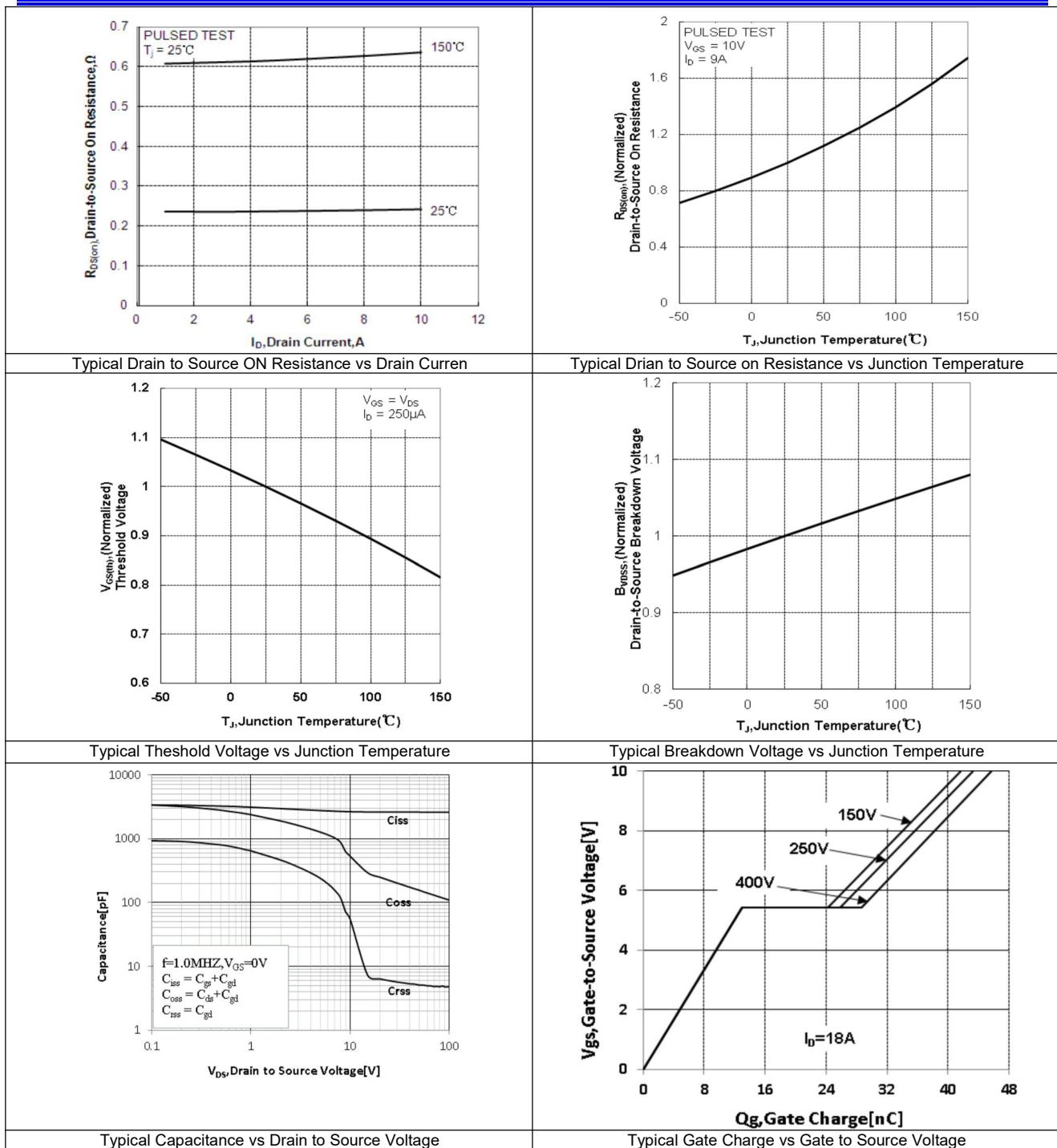
3: Pulse width ≤ 300μs, duty cycle ≤ 2%.

4: L=10mH,I_D=14.5A,V_{DD}=50V,,Start T_J=25°C.

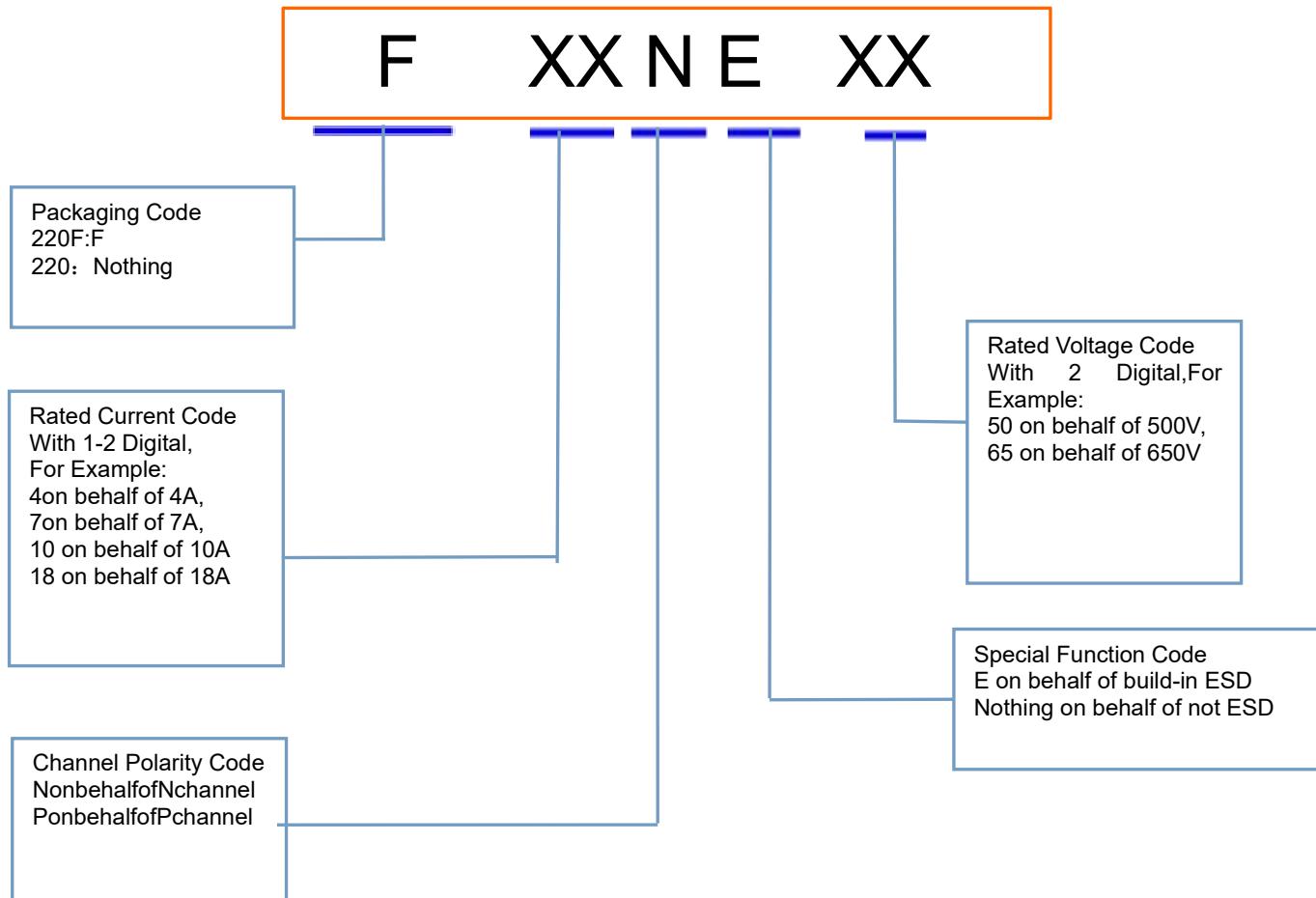
5 Typical Test Circuit and Waveform

<p>Gate Charge Test Circuit</p> <p>Circuit diagram showing a MOSFET (D.U.T.) connected between V_{DD} and ground. The gate is connected to a voltage source V_{GS} through a resistor R_G and a current source of 1 mA. The drain current I_D is measured. The drain voltage V_{DS} is also indicated.</p>	<p>Gate Charge Waveforms</p> <p>Graph showing V_{DS} and V_{GS} versus time. The x-axis shows t_{d(ON)}, t_{rise}, t_{d(OFF)}, and t_{fall}. The y-axis shows V_{DS} and V_{GS}. The waveforms show the drain voltage V_{DS} dropping to 10% of its maximum value during the turn-off transition.</p>
<p>Resistive Switching Test Circuit</p> <p>Circuit diagram showing a MOSFET (D.U.T.) connected between V_{DD} and ground. A current pump is connected to the drain terminal. A double pulse generator provides a current pulse to the drain. The drain current I_D is measured. The drain voltage V_{DS} is also indicated.</p>	<p>Resistive Switching Waveforms</p> <p>Graph showing I_D versus time. The x-axis shows t_{rr}. The y-axis shows I_D. The graph shows the drain current I_D during a reverse recovery cycle, with a peak current labeled Q_{rr} and a time interval t_{rr} indicated.</p>
<p>Diode Reverse Recovery Test Circuit</p> <p>Circuit diagram showing a MOSFET (D.U.T.) connected between V_{DD} and ground. A series switch (MOSFET) is connected in parallel with the D.U.T. A commuting diode is connected in series with the drain. The drain voltage V_{DS} is measured. The drain current I_D is measured through a 50Ω resistor. The gate voltage V_{GS} is also indicated.</p>	<p>Diode Reverse Recovery Waveform</p> <p>Graph showing V_{DS} and I_D versus time. The x-axis shows t_{AV}. The y-axis shows V_{DS} and I_D. The graph shows the drain voltage V_{DS} dropping to zero during reverse recovery, with a peak current I_{AS} and a time interval t_{AV} indicated.</p>
<p>Unclamped Inductive Switching Test Circuit</p> <p>Circuit diagram showing a MOSFET (D.U.T.) connected between V_{DD} and ground. A series switch (MOSFET) is connected in parallel with the D.U.T. A commuting diode is connected in series with the drain. The drain voltage V_{DS} is measured. The drain current I_D is measured through a 50Ω resistor. The gate voltage V_{GS} is also indicated.</p>	<p>Unclamped Inductive Switching Waveform</p> <p>Graph showing V_{DS} and I_D versus time. The x-axis shows t_p. The y-axis shows V_{DS} and I_D. The graph shows the drain voltage V_{DS} dropping to zero during unclamped inductive switching, with a peak current I_{AS} and a time interval t_p indicated. The formula for energy dissipation is given as $E_{AS} = \frac{I_{AS}^2 L}{2}$.</p>





7 Product Names Rules

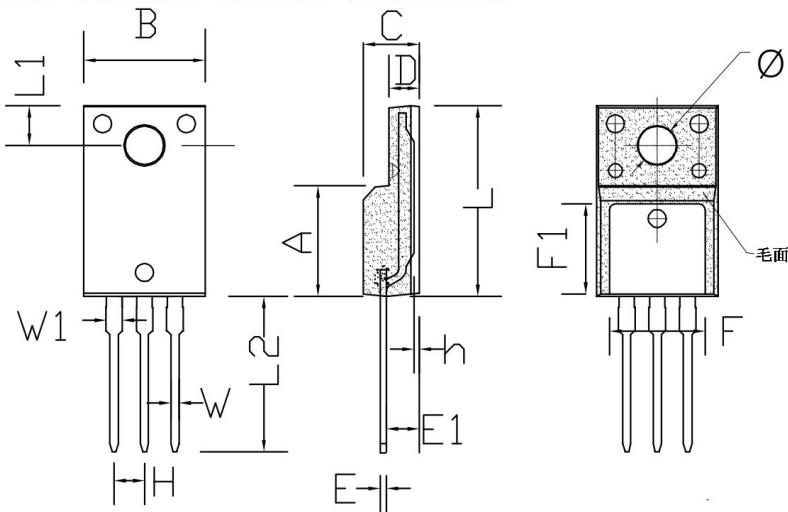


8 Product Specifications and Packaging Models

Product Model	Package Type	Mark Name	RoHS	Package	Quantity
F18N50	TO-220F	F18N50	Pb-free	Tube	1000/box

9 Dimensions

TO-220F PACKAGE OUTLINE DIMENSIONS



Symbol	DimensionsIn Millimeters		DimensionsIn Inches	
	min.	max.	min.	max.
A	8.80	9.30	0.346	0.366
B	10.00	10.50	0.394	0.413
C	4.30	4.90	0.169	0.193
D	2.30	2.70	0.091	0.106
L	15.55	16.15	0.612	0.636
h	0.40	0.60	0.016	0.024
L1	3.15	3.55	0.124	0.140
L2	12.65	13.35	0.498	0.526
W	0.70	0.90	0.028	0.035
W1	1.15	1.55	0.045	0.061
H	2.54 TYP		0.100 TYP	
E	0.48	0.53	0.019	0.021
Φ	2.90	3.40	0.114	0.134
E1	2.40	2.90	0.094	0.114
F	7.75	8.25	0.305	0.325
F1	7.35	7.85	0.289	0.309

10 Attenions

- Jiangsu Donghai Semiconductor Co.,Ltd. reserves the right to change the specification without prior notice! The customer should obtain the latest version of the information before making the order and verify that the information is complete and up to date.
- It is the responsibility of the purchaser for any failure or failure of any semiconductor product under certain conditions. It is the responsibility of the purchaser to comply with safety standards and to take safety measures in the system design and machine manufacturing of Jiangsu Donghai Semiconductor Co.,Ltd. products in order to avoid potential risk of failure. Injury or property damage.
- Product promotion is endless, our company will be dedicated to provide customers with better products.

11 Appendix

Revision history:

Date	REV.	Description	Page
2020.03.09	1.0	Original	
2022.01.01	1.1	Modify company name	all